



FEINMETALL
Contact technologies for electronics

FMnewsletter

March 2011

A personal conversation...

...cannot be replaced by anything.
Visit us during the next SMT in Nuremberg! You will find us in hall 6, booth 209.



SMT HYBRID PACKAGING

Systemintegration in der Mikroelektronik

Messe & Kongress Nürnberg 3.-5. Mai 2011

This year we will focus on following solutions:

- Compact fixture for small batches or development environment
- Finepitch-fixture with rigid probes
- Contact probes for high current applications
- High-frequency probes

We look forward to meeting you!

Do you have questions or do you require further information? The FEINMETALL team is pleased to assist you!

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SPRING CONTACT PROBES

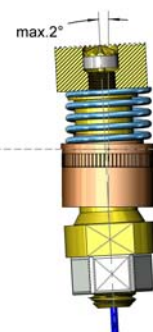
New Progressive Series Tip Style

Our contact probes for contacting lead-free soldering pads and strongly contaminated PCBs are already performing extremely well in practice. The higher preload and the functional coating for reduced contamination lead to considerably increased reliability and lifetime of the contact probes. Now, the 100mil-probe F100 with wobbling plunger is available as "progressive series" version. Additional variants are following soon.



SPRING CONTACT PROBES

High-Current Kelvin Measurement



Coaxial high current probes are often used for a 4-pole resistance test (Kelvin test), being able to measure also very low resistances precisely. Kelvin high-current probes have two electrically insulated measuring circuits. A determined current is applied to the outer conductor (force signal) whilst the resulting voltage is detected by the inner conductor (sense signal). Another application example is the control of the charging and discharging process when priming battery cells. The contact probe 1860C004 allows currents up to 150 Amps and due to its clever design it can adapt to an inclined surface, similar to a float-mounted compass.

[Details](#)

SUCCESSFUL AUDIT

ISO and VDA Certificates Renewed



We have just successfully concluded the repetition audit for the ISO 9001 and VDA 6.1 standards as well as the surveillance audit for the ISO 14001 standard. Our excellent project management in the spring contact probe division was especially highlighted. This is a great motivation for all our teams!

TEST FIXTURES

Fixtures with Rigid Probes



PCBs in modern technical equipments need to be smaller and smaller, the track structures become finer and finer. These small grids require new test solutions. Fixtures with rigid probes are smart and cost-effective solutions for the test of fine pitch PCBs. These fixtures work according to the following principle: By using slightly deviated rigid probes the fine pitch of a DUT is transferred to a standard pitch (e.g. 100mil) in a second level. By this measure the distance between test points is enlarged and these enlarged test points can be contacted by standard probes. Centers of 30mil can be easily tested with a rigid probe fixture. But even for 50mil centers it might make sense to use a rigid probe fixture, because the combination of rigid probes and 100mil standard probes can be more cost-effective than using 50mil probes. Especially for a large number of test points in 50mil centers this can be a very economic way of testing.

WAFER PROBE CARDS

Expertise in Asia



The worldwide production of semiconductors is currently at a high level, expecting enormous growth especially in China. Own FEINMETALL offices in Singapore and Taiwan offer a high level of competence and local assistance to our Asian semiconductor customers. Focusing on this market development, the Wafer Probe Card Division of FEINMETALL is participating at this year's Semicon China Show.